



Plot 7-1230. Conducted Spurious Emission Plot 1.992 GHz to 2.108 GHz (Multi Band_B2_5M_1C_High + B66_5M_1C_Low_QPSK - Port 0)



Plot 7-1231. Conducted Spurious Emission Plot 2.182 GHz to 6 GHz $(Multi\ Band_B2_5M_1C_High + B66_5M_1C_Low_QPSK - Port\ 2)$



Plot 7-1232. Conducted Spurious Emission Plot 6 GHz to 22 GHz (Multi Band_B2_5M_1C_High + B66_5M_1C_Low_QPSK - Port 1)

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Configuration	Port	Measurement Range	Level (dBm)	Limit (dBm)	Worst Margin (dB)
		9 kHz to 150 kHz	-59.43	-49.02	-10.41
		150 kHz to 30 MHz	-59.87	-39.02	-20.85
		30 MHz to 1 GHz	-53.80	-29.02	-24.78
	0	1 GHz to 1.928 GHz	-28.74	-19.02	-9.72
		1.992 GHz to 2.108 GHz	-30.56	-19.02	-11.54
		2.182 GHz to 6 GHz	-26.35	-19.02	-7.33
		6 GHz to 22 GHz	-26.19	-19.02	-7.17
		9 kHz to 150 kHz	-59.50	-49.02	-10.48
		150 kHz to 30 MHz	-60.34	-39.02	-21.32
		30 MHz to 1 GHz	-50.05	-29.02	-21.03
	1	1 GHz to 1.928 GHz	-29.06	-19.02	-10.04
		1.992 GHz to 2.108 GHz	-30.01	-19.02	-10.99
Multi Band		2.182 GHz to 6 GHz	-27.08	-19.02	-8.06
B2_5M+5M+5M 3C Low +		6 GHz to 22 GHz	-26.69	-19.02	-7.67
B66_5M+5M+5M_		9 kHz to 150 kHz	-60.18	-49.02	-11.16
3C_High		150 kHz to 30 MHz	-61.39	-39.02	-22.37
		30 MHz to 1 GHz	-51.28	-29.02	-22.26
	2	1 GHz to 1.928 GHz	-29.13	-19.02	-10.11
		1.992 GHz to 2.108 GHz	-29.92	-19.02	-10.90
		2.182 GHz to 6 GHz	-24.54	-19.02	-5.52
		6 GHz to 22 GHz	-26.65	-19.02	-7.63
		9 kHz to 150 kHz	-60.28	-49.02	-11.26
		150 kHz to 30 MHz	-60.43	-39.02	-21.41
		30 MHz to 1 GHz	-51.47	-29.02	-22.45
	3	1 GHz to 1.928 GHz	-27.33	-19.02	-8.31
		1.992 GHz to 2.108 GHz	-30.34	-19.02	-11.32
		2.182 GHz to 6 GHz	-25.09	-19.02	-6.07
		6 GHz to 22 GHz	-26.38	-19.02	-7.36

Table 7-252. Conducted Spurious Emission Summary Data (Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High)

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Configuration	Port	Measurement Range	Level (dBm)	Limit (dBm)	Worst Margin (dB)
		9 kHz to 150 kHz	-59.98	-49.02	-10.96
		150 kHz to 30 MHz	-62.95	-39.02	-23.93
		30 MHz to 1 GHz	-52.61	-29.02	-23.59
	0	1 GHz to 1.928 GHz	-28.07	-19.02	-9.05
		1.992 GHz to 2.108 GHz	-30.23	-19.02	-11.21
		2.182 GHz to 6 GHz	-26.85	-19.02	-7.83
		6 GHz to 22 GHz	-25.87	-19.02	-6.85
		9 kHz to 150 kHz	-59.39	-49.02	-10.37
		150 kHz to 30 MHz	-60.49	-39.02	-21.47
		30 MHz to 1 GHz	-50.63	-29.02	-21.61
	1	1 GHz to 1.928 GHz	-28.67	-19.02	-9.65
		1.992 GHz to 2.108 GHz	-31.37	-19.02	-12.35
Multi Band_		2.182 GHz to 6 GHz	-26.97	-19.02	-7.95
B2_5M+5M+5M_3C		6 GHz to 22 GHz	-26.48	-19.02	-7.46
_High + B66_5M+5M+5M		9 kHz to 150 kHz	-60.08	-49.02	-11.06
_3C_Low		150 kHz to 30 MHz	-61.14	-39.02	-22.12
		30 MHz to 1 GHz	-50.39	-29.02	-21.37
	2	1 GHz to 1.928 GHz	-27.73	-19.02	-8.71
		1.992 GHz to 2.108 GHz	-31.03	-19.02	-12.01
		2.182 GHz to 6 GHz	-25.05	-19.02	-6.03
		6 GHz to 22 GHz	-26.41	-19.02	-7.39
		9 kHz to 150 kHz	-59.99	-49.02	-10.97
		150 kHz to 30 MHz	-60.39	-39.02	-21.37
		30 MHz to 1 GHz	-51.73	-29.02	-22.71
	3	1 GHz to 1.928 GHz	-27.64	-19.02	-8.62
		1.992 GHz to 2.108 GHz	-31.20	-19.02	-12.18
		2.182 GHz to 6 GHz	-26.47	-19.02	-7.45
		6 GHz to 22 GHz	-26.52	-19.02	-7.50

Table 7-253. Conducted Spurious Emission Summary Data (Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low)

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Plot 7-1233. Conducted Spurious Emission Plot 9 kHz to 150 kHz

(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 0)



Plot 7-1235. Conducted Spurious Emission Plot 30 MHz to 1 GHz

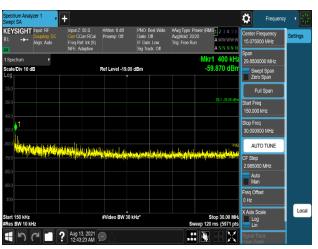
(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 1)



Plot 7-1237. Conducted Spurious Emission Plot 1.992 GHz to 2.108 GHz

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(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 2)



Plot 7-1234. Conducted Spurious Emission Plot 150 kHz to 30 MHz

(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 0)



Plot 7-1236. Conducted Spurious Emission Plot 1 GHz to 1.928 GHz

(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 3)



Plot 7-1238. Conducted Spurious Emission Plot 2.182 GHz to 6 GHz

(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 2)

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Plot 7-1239. Conducted Spurious Emission Plot 6 GHz to 22 GHz

(Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High_QPSK - Port 0)



Plot 7-1240. Conducted Spurious Emission Plot 9 kHz to 150 kHz

(Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low_QPSK - Port 1)



Plot 7-1241. Conducted Spurious Emission Plot 150 kHz to 30 MHz

(Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low_QPSK - Port 3)



Plot 7-1242. Conducted Spurious Emission Plot 30 MHz to 1 GHz

 $(Multi\ Band_B2_5M+5M+5M_3C_High+B66_5M+5M+5M_3C_Low_QPSK-Port\ 2)$



Plot 7-1243. Conducted Spurious Emission Plot 1 GHz to 1.928 GHz

(Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low_QPSK - Port 3)

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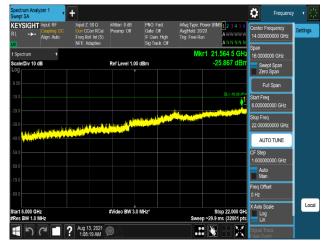




Plot 7-1244. Conducted Spurious Emission Plot 1.992 GHz to 2.108 GHz (Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low_QPSK - Port 0)

| Spectrum | Spectrum

Plot 7-1245. Conducted Spurious Emission Plot 2.182 GHz to 6 GHz (Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low_QPSK - Port 3)



Plot 7-1246. Conducted Spurious Emission Plot 6 GHz to 22 GHz (Multi Band_B2_5M+5M+5M_3C_High + B66_5M+5M+5M_3C_Low_QPSK - Port 0)

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Configuration	Port	Measurement Range	Level (dBm)	Limit (dBm)	Worst Margin (dB)
		9 kHz to 150 kHz	-59.63	-49.02	-10.61
		150 kHz to 30 MHz	-61.35	-39.02	-22.33
		30 MHz to 1 GHz	-54.19	-29.02	-25.17
	0	1 GHz to 1.928 GHz	-28.61	-19.02	-9.59
		1.992 GHz to 2.108 GHz	-30.77	-19.02	-11.75
		2.182 GHz to 6 GHz	-26.58	-19.02	-7.56
		6 GHz to 22 GHz	-26.16	-19.02	-7.14
		9 kHz to 150 kHz	-59.58	-49.02	-10.56
		150 kHz to 30 MHz	-60.68	-39.02	-21.66
		30 MHz to 1 GHz	-51.29	-29.02	-22.27
	1	1 GHz to 1.928 GHz	-29.12	-19.02	-10.10
		1.992 GHz to 2.108 GHz	-30.12	-19.02	-11.10
Multi Band_		2.182 GHz to 6 GHz	-26.43	-19.02	-7.41
B2_5M+5M+5M_3C - Non-contiguous+		6 GHz to 22 GHz	-26.25	-19.02	-7.23
B66_5M+5M+5M_3C		9 kHz to 150 kHz	-59.50	-49.02	-10.48
-Non-contiguous		150 kHz to 30 MHz	-61.12	-39.02	-22.10
		30 MHz to 1 GHz	-51.23	-29.02	-22.21
	2	1 GHz to 1.928 GHz	-27.92	-19.02	-8.90
		1.992 GHz to 2.108 GHz	-31.21	-19.02	-12.19
		2.182 GHz to 6 GHz	-24.45	-19.02	-5.43
		6 GHz to 22 GHz	-26.34	-19.02	-7.32
		9 kHz to 150 kHz	-60.24	-49.02	-11.22
		150 kHz to 30 MHz	-61.91	-39.02	-22.89
		30 MHz to 1 GHz	-52.19	-29.02	-23.17
	3	1 GHz to 1.928 GHz	-28.25	-19.02	-9.23
		1.992 GHz to 2.108 GHz	-31.30	-19.02	-12.28
		2.182 GHz to 6 GHz	-27.01	-19.02	-7.99
		6 GHz to 22 GHz	-26.27	-19.02	-7.25

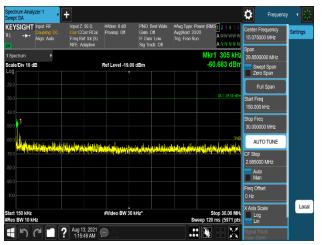
Table 7-254. Conducted Spurious Emission Summary Data (Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous)

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Plot 7-1247. Conducted Spurious Emission Plot 9 kHz to 150 kHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 2



Plot 7-1248. Conducted Spurious Emission Plot 150 kHz to 30 MHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 1



Plot 7-1249. Conducted Spurious Emission Plot 30 MHz to 1 GHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 2



Plot 7-1250. Conducted Spurious Emission Plot 1 GHz to 1.928 GHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 2



Plot 7-1251. Conducted Spurious Emission Plot 1.992 GHz to 2.108 GHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 1



Plot 7-1252. Conducted Spurious Emission Plot 2.182 GHz to 6 GHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 2

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Plot 7-1253. Conducted Spurious Emission Plot 6 GHz to 22 GHz Multi Band_B2_5M+5M+5M_3C - Non-contiguous + B66_5M+5M+5M_3C - Non-contiguous_QPSK - Port 0

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7.8 Radiated spurious emission

Test Overview

Radiated spurious emissions measurements are performed using the field strength method described in ANSI C63.26-2015 with the EUT transmitting into an integral antenna or attached antenna directly to the transmitter. Measurements on signals operating below 1GHz are performed using vertically and horizonally polarized broadband tri-log antennas. Measurements on signals operating above 1GHz are performed using vertically and horizontally polarized broadband horn antennas.

Test Procedure Used

ANSI C63.26 - Section 5.5.3.2

Test Setting

- 1. Start frequency was set to 30 MHz and stop frequency was set to at least 10 * the fundamental frequency
- 2. RBW = 100 kHz for emissions below 1 GHz and 1 MHz for emissions above 1GHz
- 3. VBW ≥ 3 x RBW
- 4. No. of sweep points > 2 x span / RBW
- 5. Detector = Peak for the pre-scan, (In cases where the level is within 2 dB of the limit, the final
- 6. measurement is taken using RMS detector.)
- 7. Trace mode = Max Hold (In cases where the level is within 2 dB of the limit, the final measurement is
- 8. taken using triggering/gating and trace averaging.)
- 9. The trace was allowed to stabilize.

Limit

The minimum permissible attenuation level of any spurious emission is $43 + log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts.

The power of any emission outside of the authorized operating frequency range cannot exeed -13 dBm.

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Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

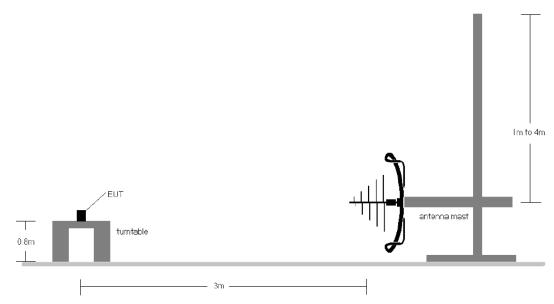


Figure 7-7. Test Instrument & Measurement Setup < 1 GHz

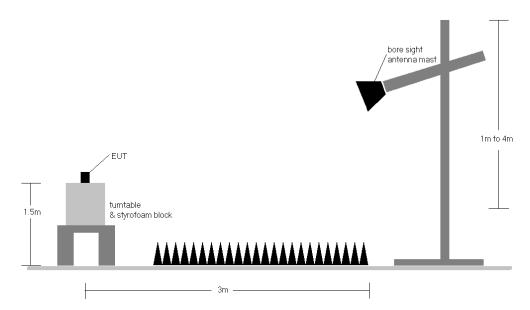


Figure 7-8. Test Instrument & Measurement Setup > 1 GHz

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Test Notes

1. The average EIRP reported below is calculated per 5.2.7 of ANSI C63.26-2015 which states: The measured e.i.r.p is converted to E-field in V/m. Then the distance correction is applied before converted back to calculated e.i.r.p.as explained in KDB 971168 D01 D01 v03r01.

Effective Isotropic Radiated Power Sample Calculation

Field Strength [dB μ V/m] = Measured Value [dBm] + AFCL [dB/m] + 107

 $= -81.64 \text{ dBm} + (23.41 \text{ dBm} + 2.69 \text{ dBm}) + 107 = 51.50 \text{ dB}\mu\text{V/m}$

 $= 10^{(51.50/20)/1000000} = 0.000374 \text{ V/m}$

e.i.r.p. [dBm] = E[dB μ V/m] + 20 log₁₀(d[m]) - 104.8

= 51.5 + (20*log(3)) - 104.8

= -43.77 dBm e.i.r.p.

*AFCL (dB/m) contains measurement antenna factor(dB/m) and cable loss(dB) as below:

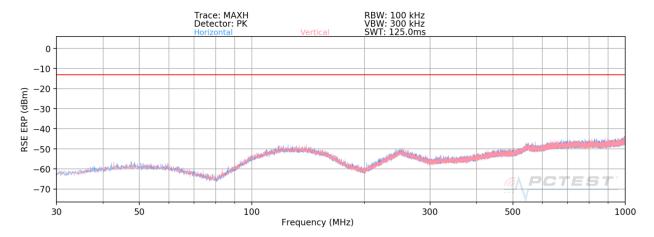
Frequency	Antenna Factor	Cable loss	AFCL
[MHz]	(dB/m)	[dB]	(dB/m)
127.82	21.78	0.92	22.70
911.68	22.62	2.57	25.19
12165.06	39.42	-23.85	15.58
17980.75	47.73	-21.84	25.89

Table 7-255. Adopted AFCL value in the calculation

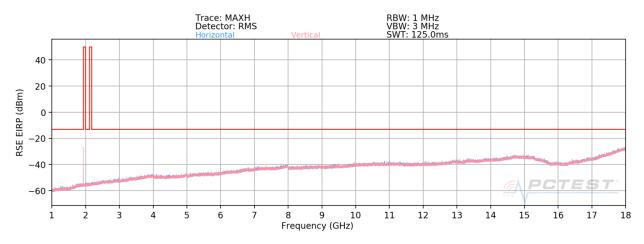
- 2. The EUT was tested in both horizontal and vertical antenna polarizations and in all possible test configurations and positioning. The worst case emissions are reported with the EUT positioning, modulations, channel bandwidth configurations shown in the tables below.
- 3. The spectrum is measured from 30 MHz to the 10th harmonic of the fundamental frequency of the transmitter. The worst-case emissions are reported.
- 4. Emissions below 18 GHz were measured at a 3 meter test distance while emissions above 18 GHz were measured at a 1 meter test distance with the application of a distance correction factor.
- 5. Spurious emissions were measured with all EUT antennas transmitting simultaneously.
- 6. The "-" shown in the following RSE tables are used to denote a noise floor measurement.

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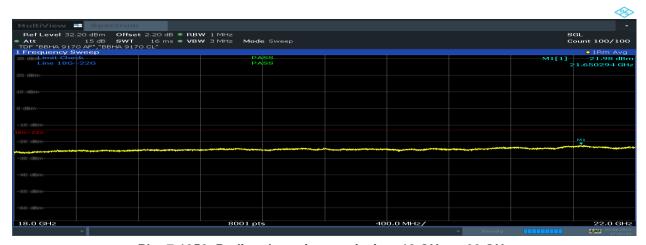




Plot 7-1254. Radiated spurious emission_30 MHz to 1000 MHz (B2_5M_1C_Low Channel)



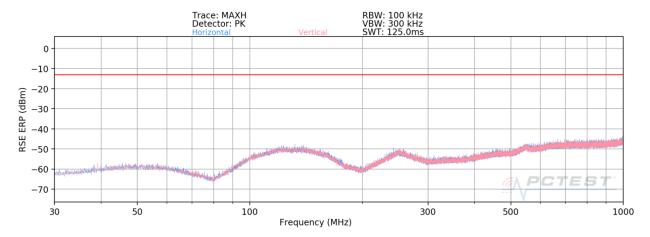
Plot 7-1255. Radiated spurious emission_1 GHz to 18 GHz (B2_5M_1C_Low Channel)



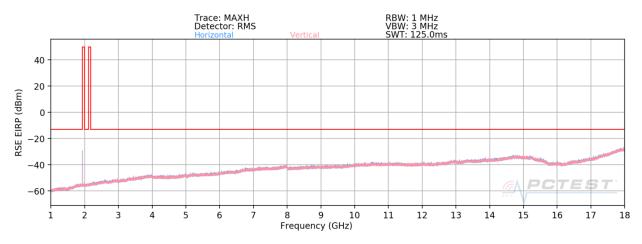
Plot 7-1256. Radiated spurious emission_18 GHz to 22 GHz (B2 5M 1C Low Channel)

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0				D14 OD 14 11 D 41

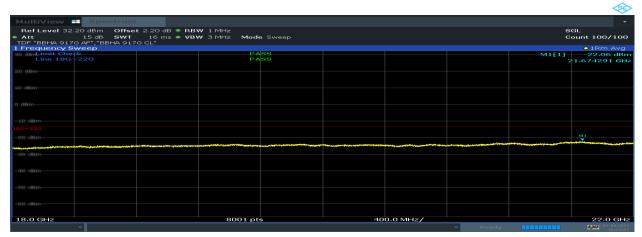




Plot 7-1257. Radiated spurious emission_30 MHz to 1000 MHz (B2_5M+5M_2C_Low Channel)



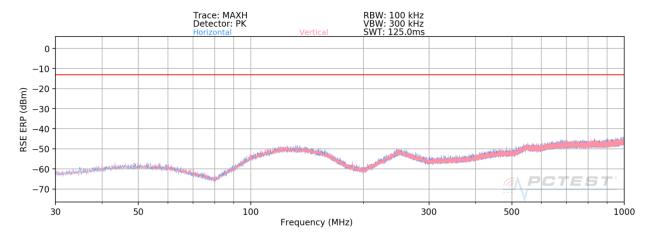
Plot 7-1258. Radiated spurious emission_1 GHz to 18 GHz (B2_5M+5M_2C_Low Channel)



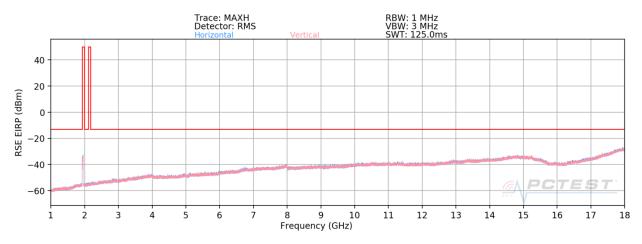
Plot 7-1259. Radiated spurious emission_18 GHz to 22 GHz (B2_5M+5M_2C_Low Channel)

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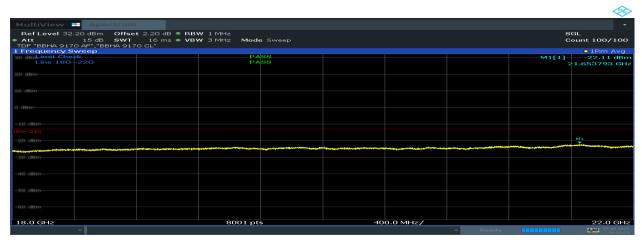




Plot 7-1260. Radiated spurious emission_30 MHz to 1000 MHz (B2_5M+5M+20M_3C_Low Channel)



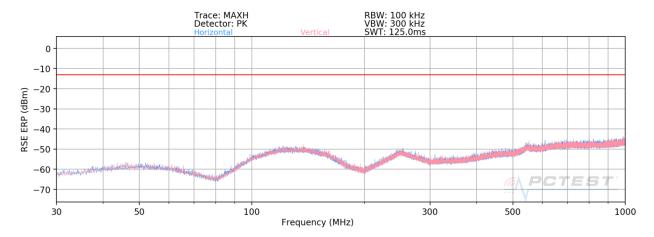
Plot 7-1261. Radiated spurious emission_1 GHz to 18 GHz (B2_5M+5M+20M_3C - Contiguous_Low Channel)



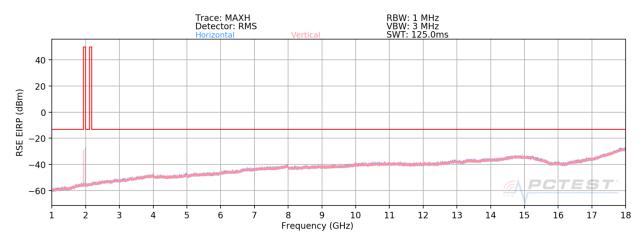
Plot 7-1262. Radiated spurious emission_18 GHz to 22 GHz (B2_5M+5M+20M_3C - Contiguous_Low Channel)

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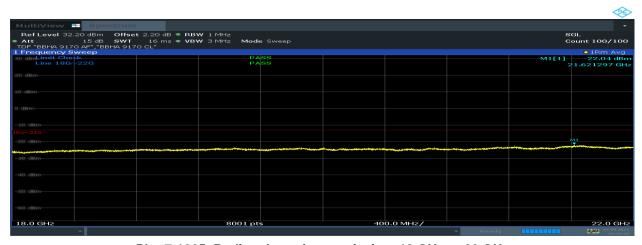




Plot 7-1263. Radiated spurious emission_30 MHz to 1000 MHz (B2_5M+5M_2C - Non-contiguous)



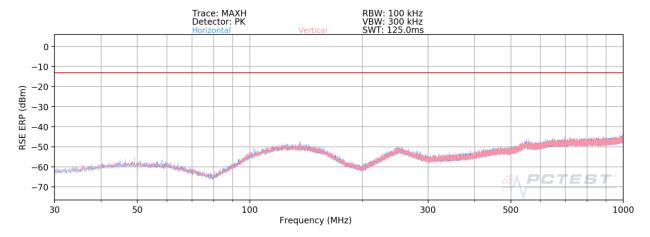
Plot 7-1264. Radiated spurious emission_1 GHz to 18 GHz (B2_5M+5M_2C - Non-contiguous)



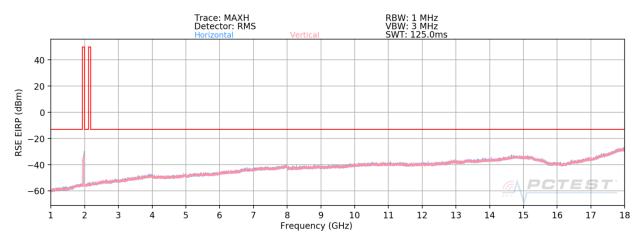
Plot 7-1265. Radiated spurious emission_18 GHz to 22 GHz (B2_5M+5M_2C - Non-contiguous)

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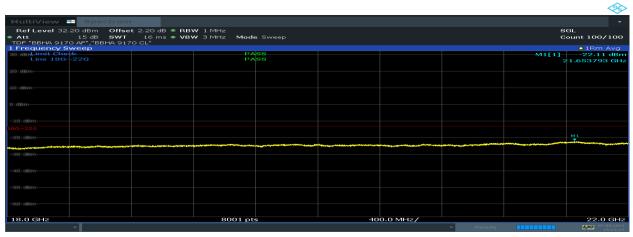




Plot 7-1266. Radiated spurious emission_30 MHz to 1000 MHz (B2_5M+5M+20M_3C - Non-contiguous)



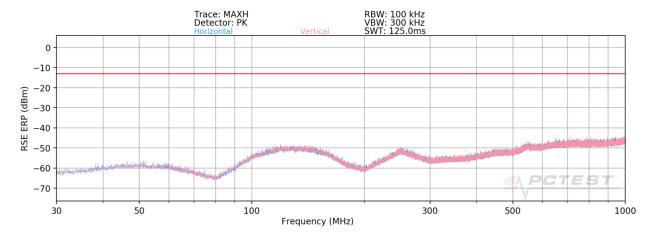
Plot 7-1267. Radiated spurious emission_1 GHz to 18 GHz (B2_5M+5M+20M_3C - Non-contiguous)



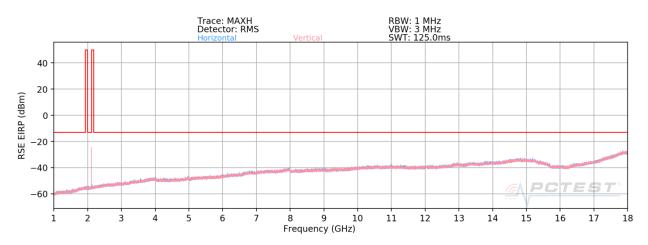
Plot 7-1268. Radiated spurious emission_18 GHz to 22 GHz (B2_5M+5M+20M_3C - Non-contiguous)

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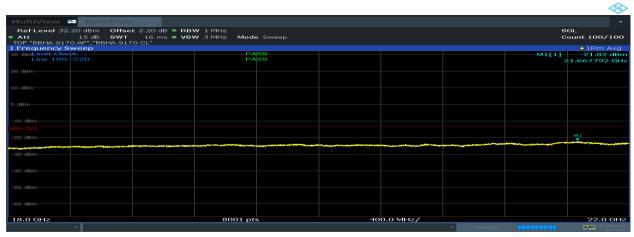




Plot 7-1269. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M_1C_Low Channel)



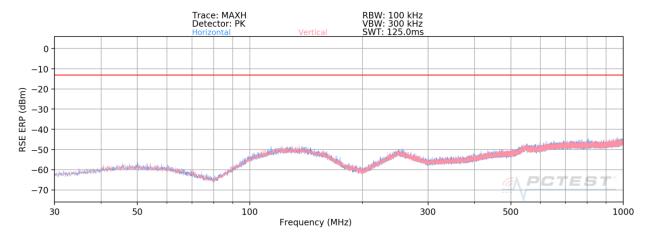
Plot 7-1270. Radiated spurious emission_1 GHz to 18 GHz (B66_5M_1C_Low Channel)



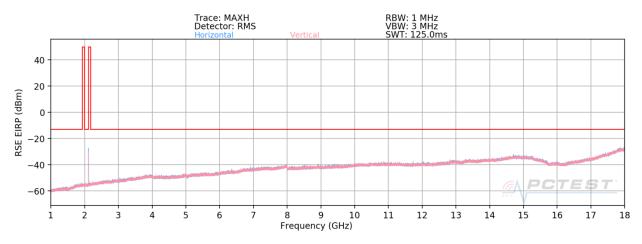
Plot 7-1271. Radiated spurious emission_18 GHz to 22 GHz (B66_5M_1C_Low Channel)

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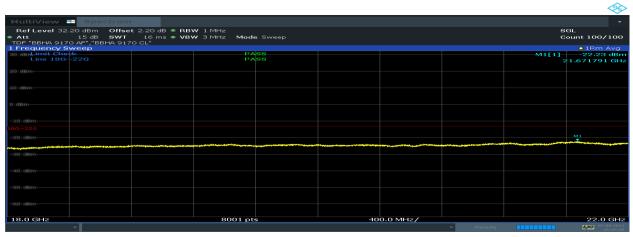




Plot 7-1272. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M+5M_2C_Low Channel)



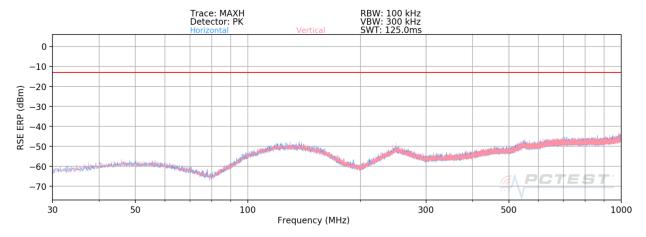
Plot 7-1273. Radiated spurious emission_1 GHz to 18 GHz (B66_5M+5M_2C_Low Channel)



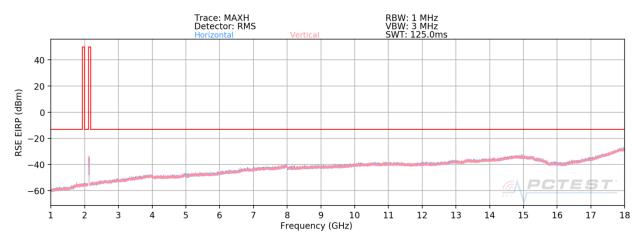
Plot 7-1274. Radiated spurious emission_18 GHz to 22 GHz (B66_5M+5M_2C_Low Channel)

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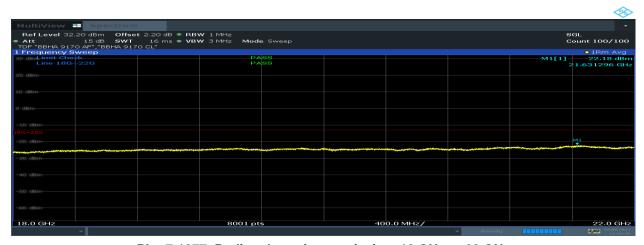




Plot 7-1275. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M+15M+20M_3C_Low Channel)



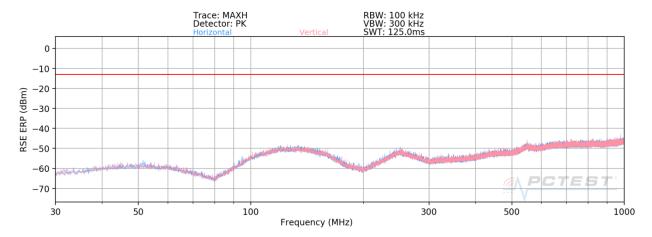
Plot 7-1276. Radiated spurious emission_1 GHz to 18 GHz (B66_5M+15M+20M_3C_Low Channel)



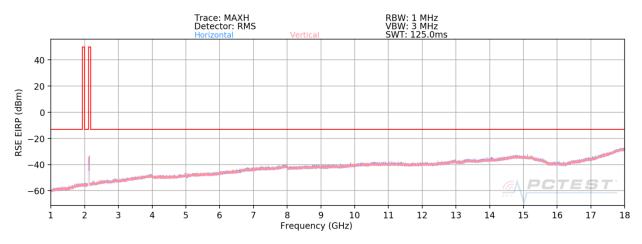
Plot 7-1277. Radiated spurious emission_18 GHz to 22 GHz (B66_5M+15M+20M_3C_Low Channel)

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O COOL DOTEOT			DI/ OD 10 11 D 01

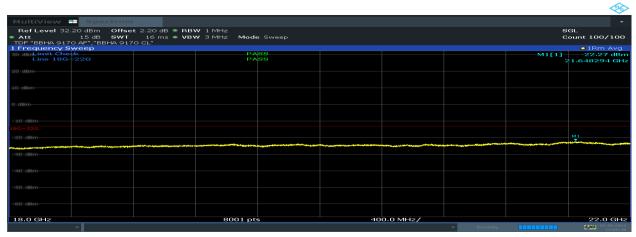




Plot 7-1278. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M+5M+10M+20M_4C_Low Channel)



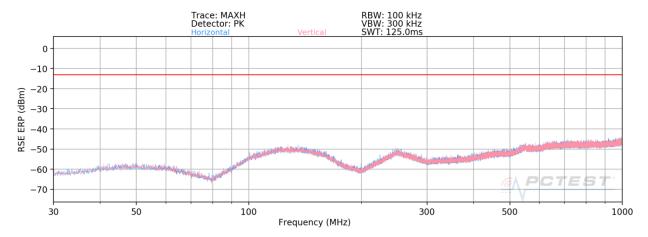
Plot 7-1279. Radiated spurious emission_1 GHz to 18 GHz (B66_5M+5M+10M+20M_4C_Low Channel)



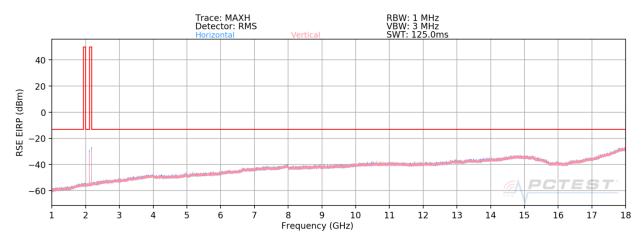
Plot 7-1280. Radiated spurious emission_18 GHz to 22 GHz (B66 5M+5M+10M+20M 4C Low Channel)

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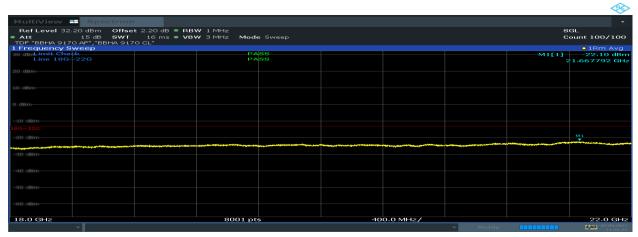




Plot 7-1281. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M+5M_2C - Non-contiguous)



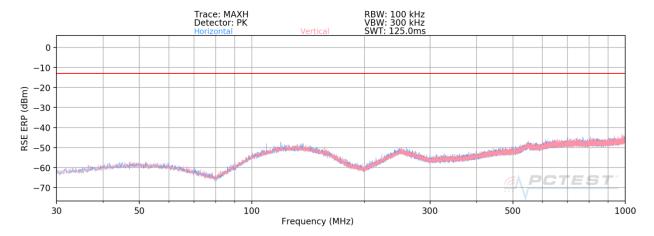
Plot 7-1282. Radiated spurious emission_1 GHz to 18 GHz (B66_5M+5M_2C - Non-contiguous)



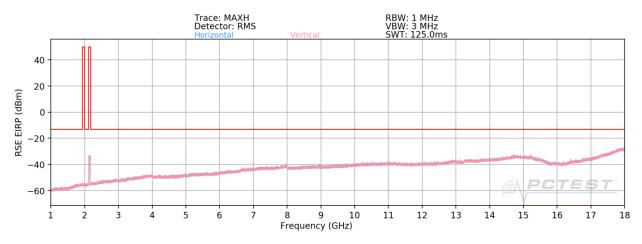
Plot 7-1283. Radiated spurious emission_18 GHz to 22 GHz (B66 5M+5M 2C - Non-contiguous)

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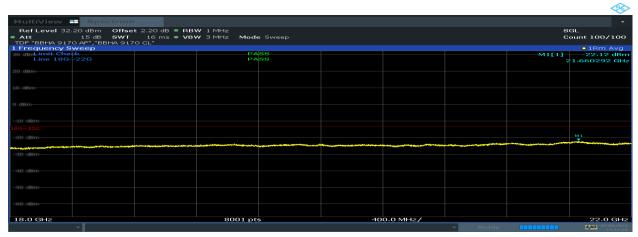




Plot 7-1284. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M+15M+20M_3C - Non-contiguous)



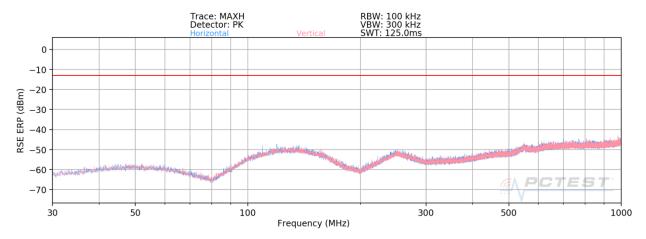
Plot 7-1285. Radiated spurious emission_1 GHz to 18 GHz (B66_5M+15M+20M_3C - Non-contiguous)



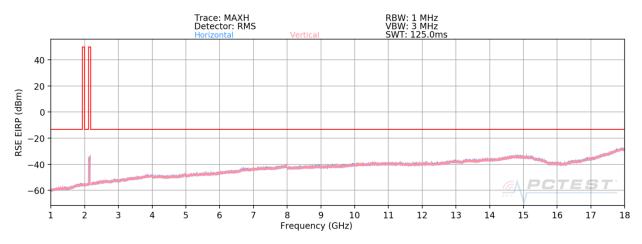
Plot 7-1286. Radiated spurious emission_18 GHz to 22 GHz (B66_5M+15M+20M_3C - Non-contiguous)

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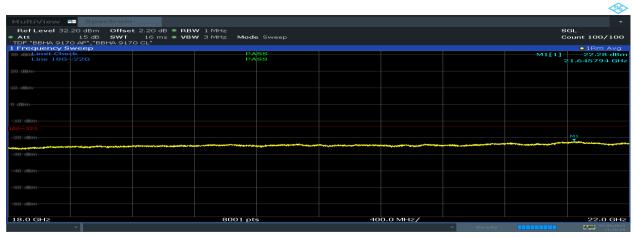




Plot 7-1287. Radiated spurious emission_30 MHz to 1000 MHz (B66_5M+5M+10M+20M_4C - Non-contiguous)



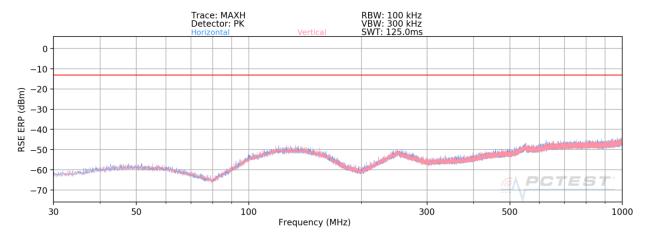
Plot 7-1288. Radiated spurious emission_1 GHz to 18 GHz (B66_5M+5M+10M+20M_4C - Non-contiguous)



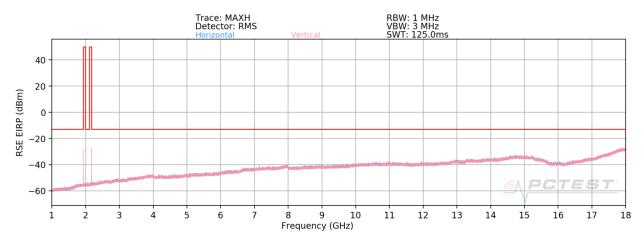
Plot 7-1289. Radiated spurious emission_18 GHz to 22 GHz (B66 5M+5M+10M+20M 4C - Non-contiguous)

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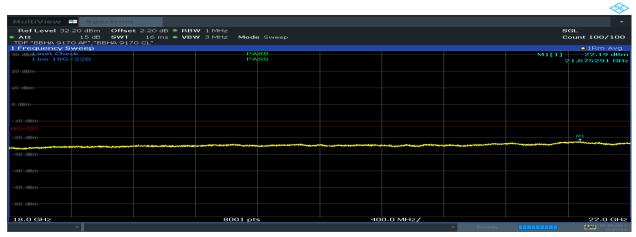




Plot 7-1290. Radiated spurious emission_30 MHz to 1000 MHz (Multi Band_B2_5M_1C_Low + B66_5M_1C_High)



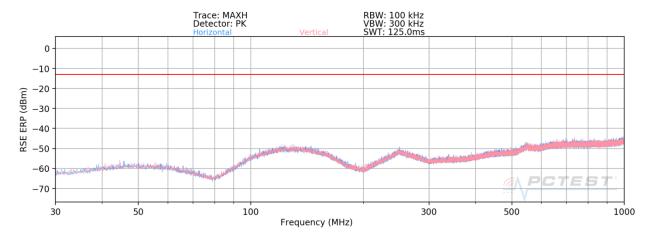
Plot 7-1291. Radiated spurious emission_1 GHz to 18 GHz (Multi Band_B2_5M_1C_Low + B66_5M_1C_High)



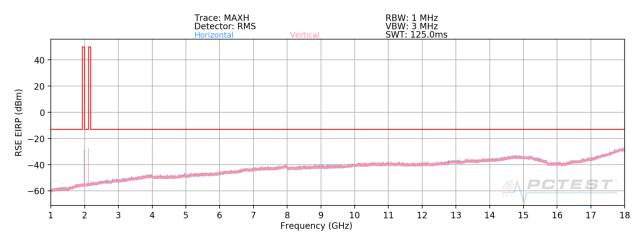
Plot 7-1292. Radiated spurious emission_18 GHz to 22 GHz (Multi Band_B2_5M_1C_Low + B66_5M_1C_High)

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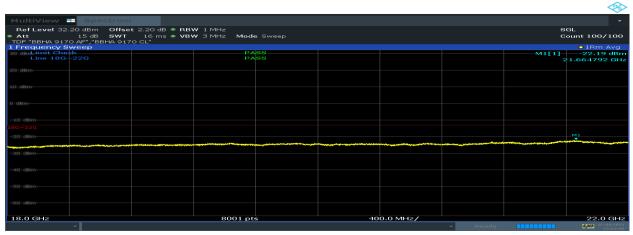




Plot 7-1293. Radiated spurious emission_30 MHz to 1000 MHz (Multi Band_B2_5M_1C_High + B66_5M_1C_Low)



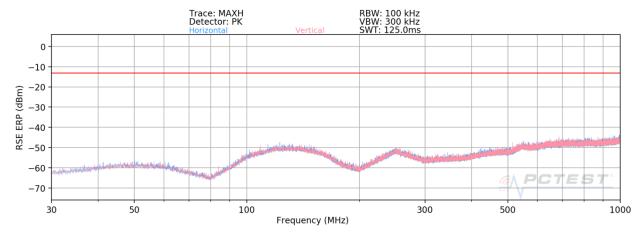
Plot 7-1294. Radiated spurious emission_1 GHz to 18 GHz (Multi Band_B2_5M_1C_High + B66_5M_1C_Low)



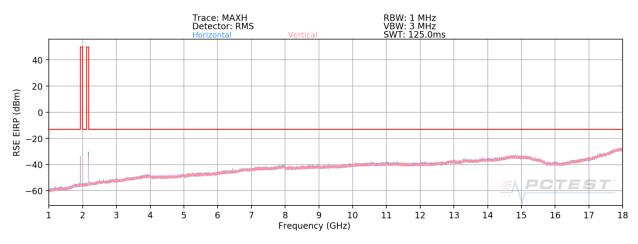
Plot 7-1295. Radiated spurious emission_18 GHz to 22 GHz (Multi Band_B2_5M_1C_High + B66_5M_1C_Low)

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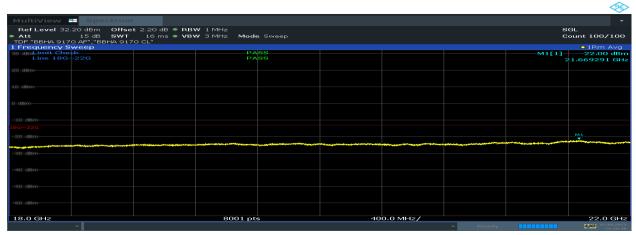




Plot 7-1296. Radiated spurious emission_30 MHz to 1000 MHz (Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High)



Plot 7-1297. Radiated spurious emission_1 GHz to 18 GHz (Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High)



Plot 7-1298. Radiated spurious emission_18 GHz to 22 GHz (Multi Band_B2_5M+5M+5M_3C_Low + B66_5M+5M+5M_3C_High)

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